## Application/Control No. Notice of References Cited Application/Control No. 10/563,441 Examiner Louis K. Huynh Applicant(s)/Patent Under Reexamination RIETJENS ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-3,909,582	09-1975	Bowen, William Edmund	219/121.69
*	В	US-4,049,945	09-1977	Ehlscheid et al.	219/121.67
*	С	US-4,160,894	07-1979	Stemmler et al.	219/121.67
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	1	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Ν	•				
	0					
	Р					
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## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.